

Notice of References Cited

Application/Control No.

10/692,516

Applicant(s)/Patent Under
Reexamination
YEOW ET AL.

Examiner

VANEL FRENEL

Art Unit

3687

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0004784	01-2003	Li et al.	705/10
*	B	US-2004/0034581	02-2004	Hill et al.	705/28
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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